

IN THE CLAIMS:

Page 13, delete line 4.

Page 13, delete lines 5-26.

Page 14, delete lines 1-4.

Page 14, delete lines 5-21.

Page 14, line 1, please insert the following new heading:

WHAT IS CLAIMED IS:

Page 14, please substitute new claims 6-9 therefor as follows:

6. (New) A probe that comes into electrical contact with an object to be inspected when inspecting an electrical characteristic of the object to be inspected, the probe comprising:

a probe main body having a contact portion that comes into contact with the object to be inspected; and a plurality of conductive materials each having a tip portion projecting from the contact portion of said probe main body.

7. (New) The probe according to claim 6,
wherein said conductive materials are buried in the contact portion and made of a material harder than the contact portion.

8. (New) The probe according to claim 6,
wherein said conductive materials are made of conductive diamond or nanoscale metal.

9. (New) A method of manufacturing a probe that comes into electrical contact with an object to be inspected when inspecting an electrical characteristic of the object to be inspected, the method comprising the steps of:

forming, on a substrate, a mold of a contact portion that comes into contact with the object to be inspected; putting in the mold a plurality of conductive materials having tip portions; forming the contact portion by filling conductive metal in the mold; forming a probe main body including the contact portion; and releasing the contact portion from the mold and making the tip portions of the conductive materials project from the contact portion.